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(12) **United States Design Patent**
Teranishi et al.

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(54) **PROBE PIN**

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324/755.01

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(**) Term: **15 Years**

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(51) **LOC (10) Cl.** **10-04**

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(52) **U.S. Cl.**

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USPC **D10/78**

(58) **Field of Classification Search**

(Continued)

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1/06711; G01R 1/06716; G01R 1/06722;
G01R 1/06727; G01R 1/06733; G01R
1/06738; G01R 1/06744; G01R 1/0675;
G01R 1/06766; G01R 1/06772; G01R
1/06777; G01R 1/06783; G01R 1/0678

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See application file for complete search history.

(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

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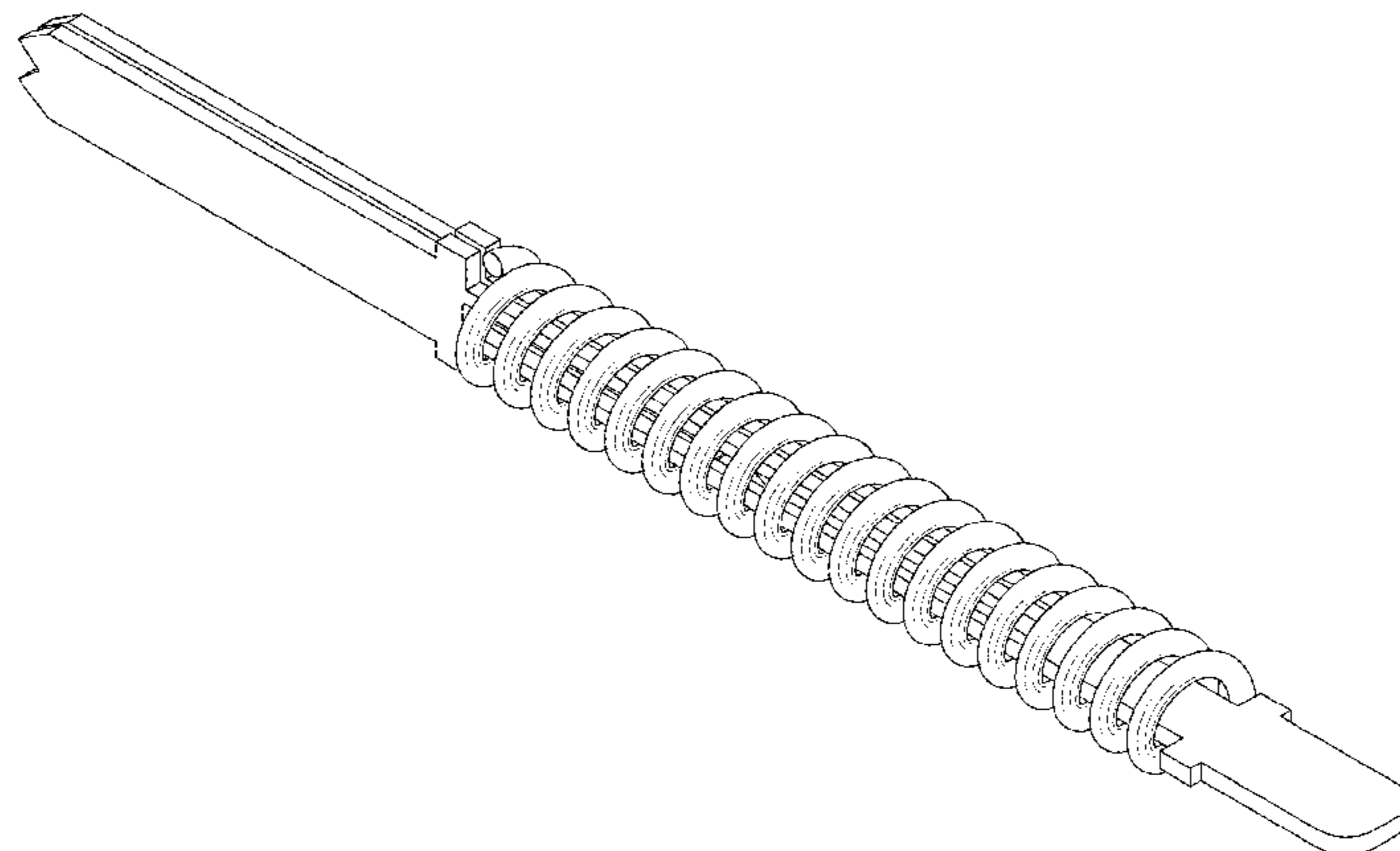
DESCRIPTION

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FIG. 1 is a perspective view of a probe pin;
FIG. 2 is a front elevation view thereof
FIG. 3 is a rear elevation view thereof
FIG. 4 is a left side view thereof
FIG. 5 is a right side view thereof;
FIG. 6 is a top plan view thereof; and,
FIG. 7 is a bottom plan view thereof.

1 Claim, 3 Drawing Sheets



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Fig. 1

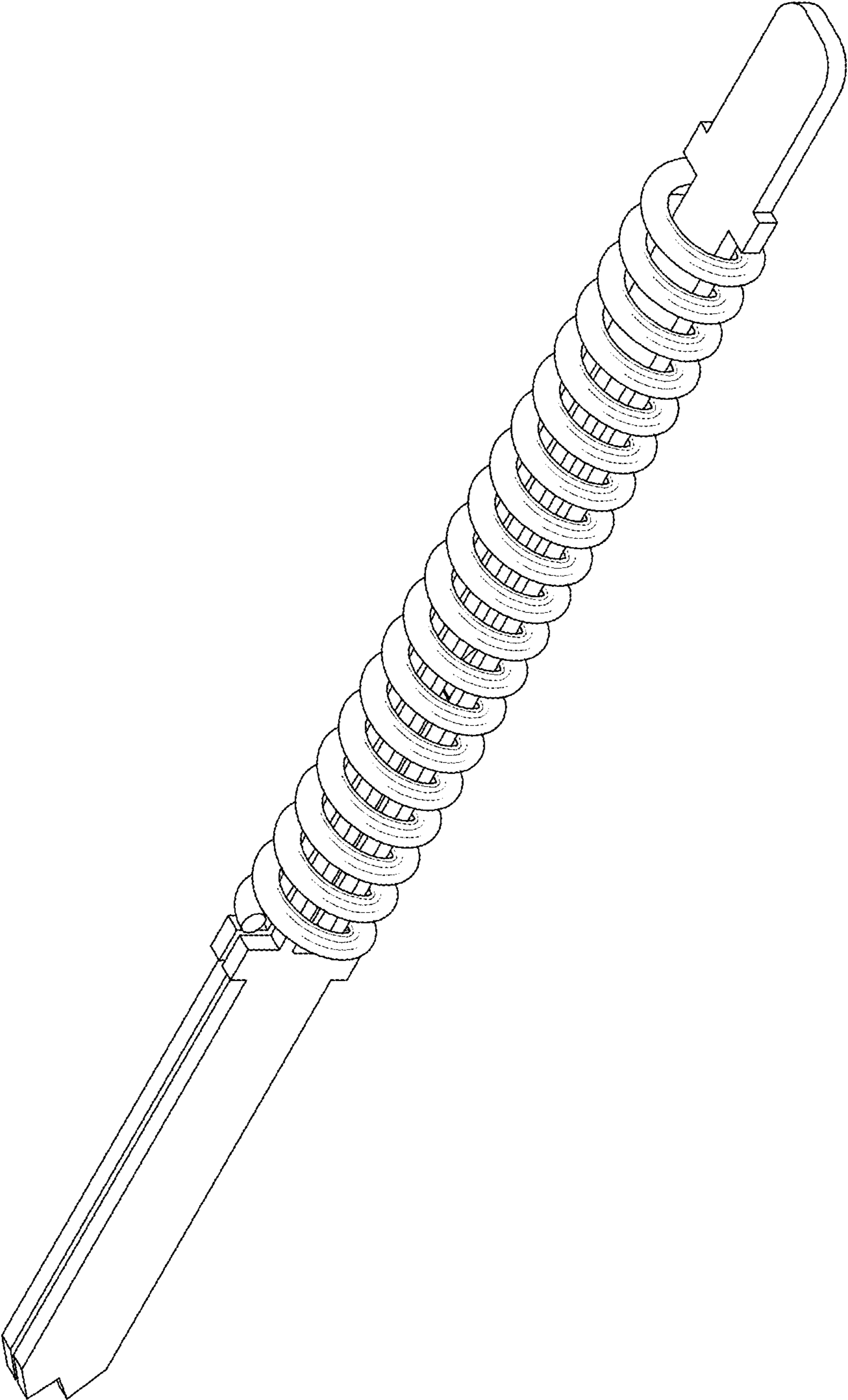


Fig. 2

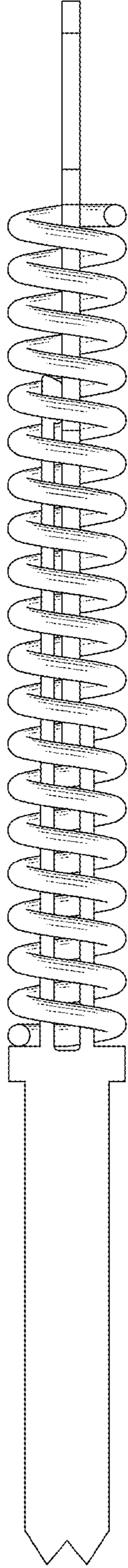


Fig. 3

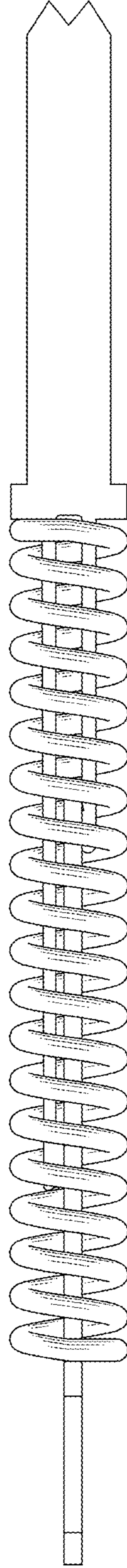


Fig. 4

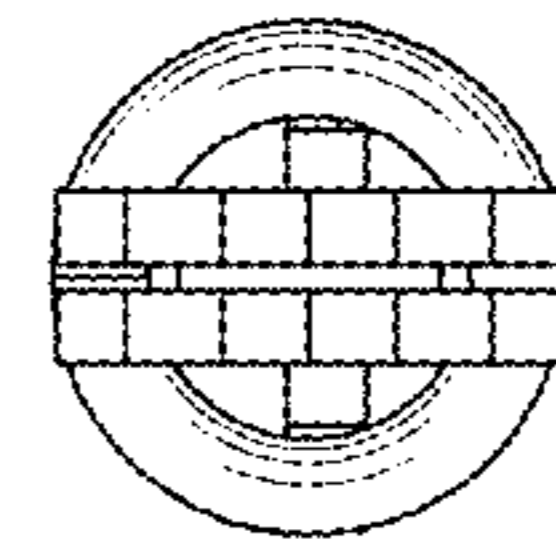


Fig. 5

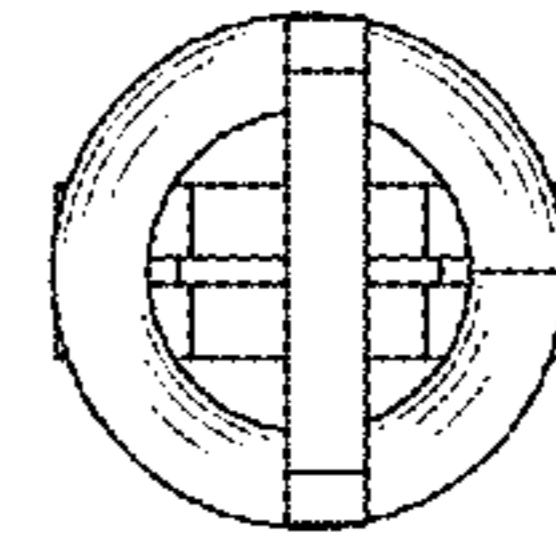


Fig. 6

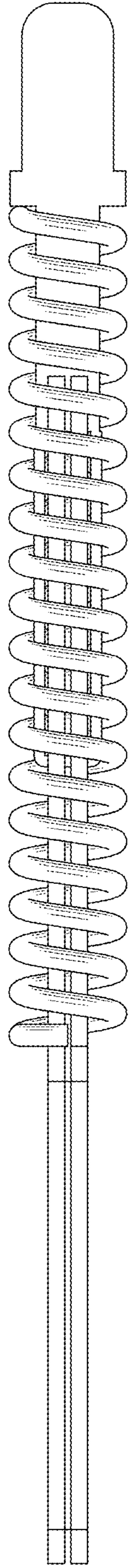


Fig. 7

